

RELIABILITY MONITOR

PROCESS: D8R-2P2M,HPVt,NDROM,N+ESD,Laser N-sub,LOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2154	A2	DEC '01	28583	0126	ATP (Amkor, PI)	DK119150AAA	LQFP	336	80	0
DS2154	A2	DEC '01	28583	0126	ATP (Amkor, PI)	DK119150AAA	LQFP	1000	80	0

TOTALS:

FAIL RATE (Fits): 12 DEVICE HRS: 7.55E+07 0

RELIABILITY MONITOR

PROCESS: 2P, 1M, 0.8um,ThinEP/Sil,ThinOx NdPdDSD,BPSG,N+ESD,CtEtch,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS87C520	A15-	FEB '02	28780	0206	ATP (Amkor, PI)	DK101111AAA	PLCC	336	77	0
DS87C520	A15-	FEB '02	28780	0206	ATP (Amkor, PI)	DK101111AAA	PLCC	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode , WJ BPSG, N+ESD II,

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	FEB '01	26609	0105	OSEP	DE047362AAB	SOIC	48	232	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	NOV '01	28558	0143	ATP (Amkor, PI)	DK122629AAB	SOIC	336	80	0
DS1803	A2	MAY '01	26993	0115	Carsem	DM052456AC	SOIC	336	77	0
DS1803	A2	MAY '01	26993	0115	Carsem	DM052456AC	SOIC	1000	76	0
DS1803	A2	AUG '01	27563	0119	OSEP	DE105519ACA	SOIC	336	80	0
DS1803	A2	FEB '01	26610	0105	OSEP	DE047362AAB	SOIC	336	77	0
DS1803	A2	FEB '01	26610	0105	OSEP	DE047362AAB	SOIC	1000	77	0

TOTALS: FAIL RATE (Fits): 4 DEVICE HRS: 2.06E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.6um,SilP1,NdA,PD,Ti/TiN M1+M2,WJ BPSG,N+ESD,CtE,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80CH11	A4	DEC '01	28601	0113	ATK (Amkor, K)	DN036754AA	LQFP	336	80	0
DS80CH11	A4	JUN '01	27107	0108	ATK (Amkor, K)	DN034351AA	LQFP	336	77	2
DS80CH11	A4	DEC '01	28601	0113	ATK (Amkor, K)	DN036754AA	LQFP	1000	80	0
DS80CH11	A4	JUN '01	27107	0108	ATK (Amkor, K)	DN034351AA	LQFP	1000	75	0
DS80CH11	A4	SEP '01	27867	0110	Stats	DC037148AA	LQFP	336	80	0
DS80CH11	A4	SEP '01	27867	0110	Stats	DC037148AA	LQFP	1000	80	0

TOTALS:

FAIL RATE (Fits): 14 DEVICE HRS: 2.22E+08 2

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.6um,E2,NZTC P1R,DSD w/LVWells, HP Vts, WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AKC	SOIC	336	77	0
DS1100	A3	OCT '01	28535	0126	ATP (Amkor, PI)	DK114601ADC	SOIC	336	77	0
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AKC	SOIC	1000	77	0

TOTALS:

FAIL RATE (Fits): 9 DEVICE HRS: 9.70E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode, Ti/TiN M1+M2 , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	AUG '01	27563	0119	OSEP	DE105519ACA	SOIC	1000	80	0

TOTALS:

FAIL RATE (Fits): 18 DEVICE HRS: 5.01E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, ESD Pdepletion,HP Vts,WJ BPSG,Ti/TiN M1+M2,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A4	SEP '01	27794	0133	ATP (Amkor, PI)	DK101008AD	PDIP	336	80	0
DS1302	A4	SEP '01	27794	0133	ATP (Amkor, PI)	DK101008AD	PDIP	1000	80	0
DS1302	A4	MAR '02	28812	0204	CPS (ChipPac, China)	DE214012AA	PDIP	336	80	0
DS1302	A4	MAR '02	28812	0204	CPS (ChipPac, China)	DE214012AA	PDIP	1000	80	0

TOTALS:

FAIL RATE (Fits): 6 DEVICE HRS: 1.51E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pd, Ti/TiN M1 , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2401	C2	MAR '02	28835	0208	Carsem	DM218006AA	SOT23	336	80	2
DS2401	C2	MAR '02	28835	0208	Carsem	DM218006AA	SOT23	1000	78	1

TOTALS:

FAIL RATE (Fits): 56 DEVICE HRS: 7.42E+07 3

RELIABILITY MONITOR

PROCESS: D6S-1P1M,HPVt,N+ESD,TCN3 ALOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	C1	MAR '02	28819	0143	ATK (Amkor, K)	DN120700ABB	SSOP	336	77	0
DS2118M	C1	MAR '02	28819	0143	ATK (Amkor, K)	DN120700ABB	SSOP	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.6um, Pdepletion, Low Vts , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21Q43	A3-	SEP '01	27880	0047	Stats	DC036714AAD	LQFP	336	70	0
DS21Q43	A3-	SEP '01	27880	0047	Stats	DC036714AAD	LQFP	1000	70	0

TOTALS:

FAIL RATE (Fits): 14 DEVICE HRS: 6.60E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um,Neg ZTC P1R,PdpID,Low Vts,BPSG ILO, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21S07	C1-	FEB '02	28808	0112	Carsem	DM048483AC	TSSOP	336	77	0

TOTALS:

FAIL RATE (Fits): 38 DEVICE HRS: 2.44E+07 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um, E2PROM, DSD w/LV Wells ,HVPchVtII,WJ BPSG,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	DEC '01	28593	0112	CPS (ChipPac, China)	DH052443AAD	SOIC	336	80	0
DS1620	D1	DEC '01	28593	0112	CPS (ChipPac, China)	DH052443AAD	SOIC	1000	80	0
DS1620	D1	SEP '01	27859	0111	NSEB	DJ051232AAI	SOIC	336	80	0
DS1620	D1	SEP '01	27859	0111	NSEB	DJ051232AAI	SOIC	1000	80	0

TOTALS:

FAIL RATE (Fits): 6 DEVICE HRS: 1.51E+08 0

RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, ZTC P1, Ndepletion ,Latell ZTC,TEOSsp,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5-5	JUL '01	27352	0110	Carsem	DM048543AA	SOT223	336	68	0
DS1233	A5-5	JUL '01	27352	0110	Carsem	DM048543AA	SOT223	1000	68	0
DS1233	A5-5	APR '01	26871	0101	Fastech	DA048537AF	SOT223	336	77	0
DS1233	A5-5	OCT '01	28006	0128	Fastech	DA102602AC	SOT223	336	68	0
DS1233	A5-5	APR '01	26871	0101	Fastech	DA048537AF	SOT223	1000	77	0
DS1233	A5-5	OCT '01	28006	0128	Fastech	DA102602AC	SOT223	1000	68	1

TOTALS:

FAIL RATE (Fits): 10 DEVICE HRS: 2.01E+08 1

RELIABILITY MONITOR

PROCESS: 1P, 1M, 2.0um, Pfield , WJ BPSG ,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175	D1	APR '01	26883	0050	ATP (Amkor, PI)	DK036683ABD	SOIC	336	77	0
DS2175	D1	APR '01	26883	0050	ATP (Amkor, PI)	DK036683ABD	SOIC	1000	77	0

TOTALS: FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

RELIABILITY MONITOR

PROCESS: 1P,1M,5.0um,NegZTC P1R,30VNF&PF,UVNd&Pd,N+ESD,TEOS,SchotP-,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B7	MAY '01	26986	0111	ATP (Amkor, PI)	DK101048AAC	SOIC	336	77	0
DS2108	B7	MAY '01	26986	0111	ATP (Amkor, PI)	DK101048AAC	SOIC	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0